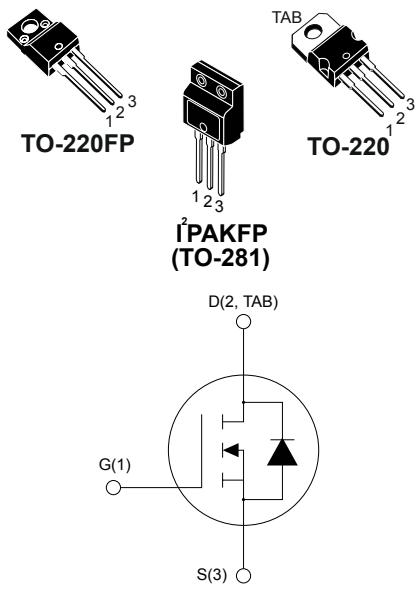


N-channel 650 V, 425 mΩ typ., 11 A MDmesh II Power MOSFETs in TO-220FP, I²PAKFP and TO-220 packages



AM01475v1_noZen

Features

Order codes	V _{DS}	R _{DS(on)} max.	I _D
STF11NM65N			
STFI11NM65N	650 V	455 mΩ	
STP11NM65N			11 A

- 100% avalanche tested
- Low input capacitance and gate charge
- Low gate input resistance

Applications

- Switching applications

Description

These devices are N-channel Power MOSFETs developed using the second generation of MDmesh technology. These revolutionary Power MOSFETs associate a vertical structure to the company's strip layout to yield one of the world's lowest on-resistance and gate charge. They are therefore suitable for the most demanding high-efficiency converters.



Product status links

[STF11NM65N](#)

[STFI11NM65N](#)

[STP11NM65N](#)

1 Electrical ratings

Table 1. Absolute maximum ratings

Symbol	Parameter	Value		Unit
		TO-220FP, I ² PAKFP	TO-220	
V _{DS}	Drain-source voltage	650		V
V _{GS}	Gate-source voltage	±25		V
I _D	Drain current (continuous) at T _C = 25 °C	11		A
	Drain current (continuous) at T _C = 100 °C	7		
I _{DM} ⁽¹⁾	Drain current (pulsed)	44		A
P _{TOT}	Total power dissipation at T _C = 25 °C	25	110	W
I _{AR}	Avalanche current, repetitive or non-repetitive (pulse width limited by T _J max)	3		A
E _{AS}	Single pulse avalanche energy (starting T _J = 25 °C, I _D = I _{AR} , V _{DD} = 50 V)	147		mJ
dv/dt ⁽²⁾	Peak diode recovery voltage slope	15		V/ns
V _{ISO}	Insulation withstand voltage (RMS) from all three leads to external heat sink (t = 1 s, T _C = 25 °C)	2.5		kV
T _{stg}	Storage temperature range	-55 to 150		°C
T _J	Operating junction temperature range			°C

1. Pulse width limited by safe operating area.
2. I_{SD} ≤ 11 A, di/dt ≤ 400 A/μs, V_{DS} (peak) ≤ V_{(BR)DSS}.

Table 2. Thermal data

Symbol	Parameter	Value		Unit
		TO-220FP, I ² PAKFP	TO-220	
R _{thJC}	Thermal resistance, junction-to-case	5	1.14	°C/W
R _{thJA}	Thermal resistance, junction-to-ambient	62.5		°C/W

2 Electrical characteristics

$T_C = 25^\circ\text{C}$ unless otherwise specified.

Table 3. On/off states

Symbol	Parameter	Test conditions	Min.	Typ.	Max.	Unit
$V_{(\text{BR})\text{DSS}}$	Drain-source breakdown voltage	$I_D = 1 \text{ mA}, V_{GS} = 0 \text{ V}$	650			V
I_{DSS}	Zero gate voltage drain current	$V_{GS} = 0 \text{ V}, V_{DS} = 650 \text{ V}$			1	μA
		$V_{GS} = 0 \text{ V}, V_{DS} = 650 \text{ V}, T_C = 125^\circ\text{C}$ (1)			100	
I_{GSS}	Gate body leakage current	$V_{GS} = \pm 25 \text{ V}, V_{DS} = 0 \text{ V}$			± 100	nA
$V_{GS(\text{th})}$	Gate threshold voltage	$V_{DS} = V_{GS}, I_D = 250 \mu\text{A}$	2	3	4	V
$R_{\text{DS(on)}}$	Static drain-source on-resistance	$V_{GS} = 10 \text{ V}, I_D = 5.5 \text{ A}$		425	455	$\text{m}\Omega$

1. Specified by design, not tested in production.

Table 4. Dynamic

Symbol	Parameter	Test conditions	Min.	Typ.	Max.	Unit
C_{iss}	Input capacitance		-	800	-	pF
C_{oss}	Output capacitance	$V_{DS} = 25 \text{ V}, f = 1 \text{ MHz}, V_{GS} = 0 \text{ V}$	-	50	-	pF
C_{rss}	Reverse transfer capacitance		-	2.9	-	pF
$C_{oss \text{ eq.}}^{(1)}$	Equivalent output capacitance	$V_{GS} = 0 \text{ V}, V_{DS} = 0 \text{ to } 520 \text{ V}$	-	133	-	pF
R_g	Intrinsic gate resistance	$f = 1 \text{ MHz}, I_D = 0 \text{ A}$	-	4.2	-	Ω
Q_g	Total gate charge		-	29	-	nC
Q_{gs}	Gate-source charge	$V_{DD} = 520 \text{ V}, I_D = 11 \text{ A}, V_{GS} = 0 \text{ to } 10 \text{ V}$ (see Figure 16. Test circuit for gate charge behavior)	-	3.9	-	nC
Q_{gd}	Gate-drain charge		-	16	-	nC

1. $C_{oss \text{ eq.}}$ is defined as the constant equivalent capacitance giving the same charging time as C_{oss} when V_{DS} increases from 0 to 80% V_{DSS} .

Table 5. Switching times

Symbol	Parameter	Test conditions	Min.	Typ.	Max.	Unit
$t_{d(on)}$	Turn-on delay time		-	15.5	-	ns
t_r	Rise time		-	10.8	-	ns
$t_{d(off)}$	Turn-off delay time	$V_{DD} = 325 \text{ V}, I_D = 5.5 \text{ A}, R_G = 4.7 \Omega,$ $V_{GS} = 10 \text{ V}$ (see Figure 15. Test circuit for resistive load switching times and Figure 20. Switching time waveform)	-	11	-	ns
t_f	Fall time		-	47	-	ns

Table 6. Source-drain diode

Symbol	Parameter	Test conditions	Min.	Typ.	Max.	Unit
I_{SD}	Source-drain current		-		11	A
I_{SDM} ⁽¹⁾	Source-drain current (pulsed)		-		44	A
V_{SD} ⁽²⁾	Forward on voltage	$I_{SD} = 11 \text{ A}, V_{GS} = 0 \text{ V}$	-		1.6	V
t_{rr}	Reverse recovery time	$I_{SD} = 11 \text{ A}, dI/dt = 100 \text{ A}/\mu\text{s}, V_{DD} = 60 \text{ V}$	-	418		ns
Q_{rr}	Reverse recovery charge	(see Figure 17. Test circuit for inductive load switching and diode recovery times)	-	4.4		μC
I_{RRM}	Reverse recovery current		-	21		A
t_{rr}	Reverse recovery time	$I_{SD} = 11 \text{ A}, dI/dt = 100 \text{ A}/\mu\text{s}, V_{DD} = 60 \text{ V}, T_J = 150 \text{ }^\circ\text{C}$ (see Figure 17. Test circuit for inductive load switching and diode recovery times)	-	530		ns
Q_{rr}	Reverse recovery charge		-	5.6		μC
I_{RRM}	Reverse recovery current		-	21		A

1. Pulse width limited by safe operating area.
2. Pulsed: pulse duration = 300 μs , duty cycle 1.5%.

Obsolete Product(s) - Obsolete Product(s)

2.1 Electrical characteristics (curves)

Figure 1. Safe operating area for TO-220FP and I²PAKFP

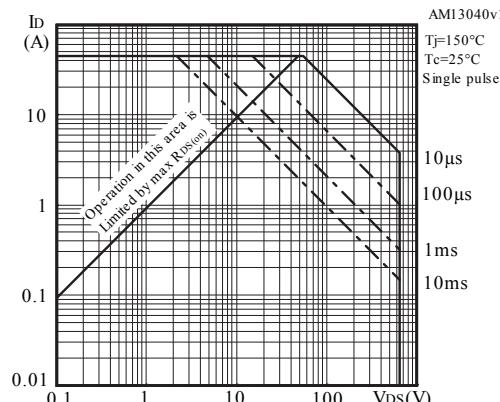


Figure 2. Normalized transient thermal impedance for TO-220FP and I²PAKFP

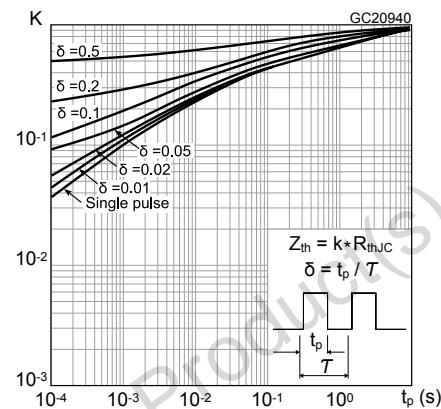


Figure 3. Safe operating area for TO-220

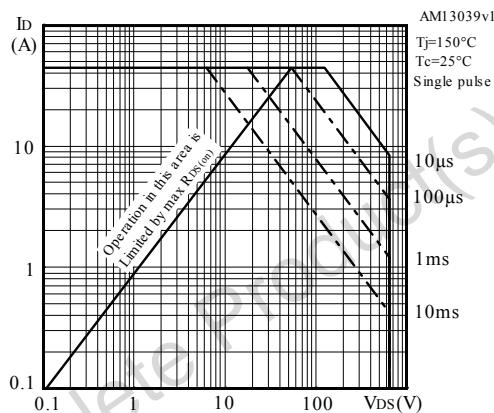


Figure 4. Normalized transient thermal impedance for TO-220

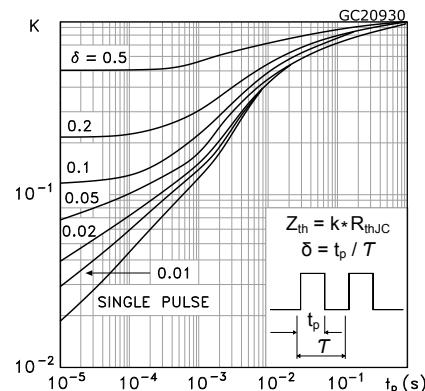


Figure 5. Typical output characteristics

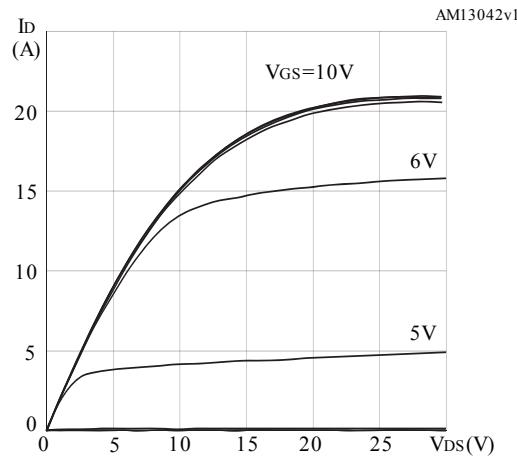


Figure 6. Typical transfer characteristics

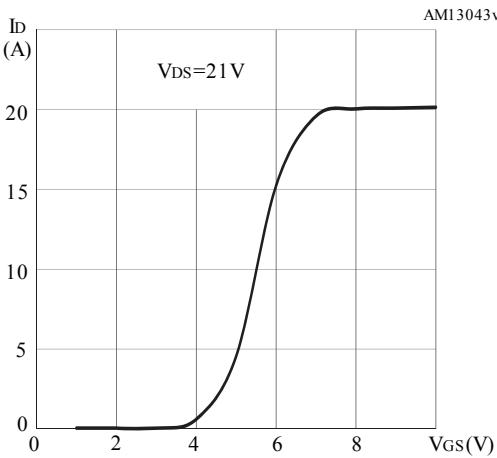


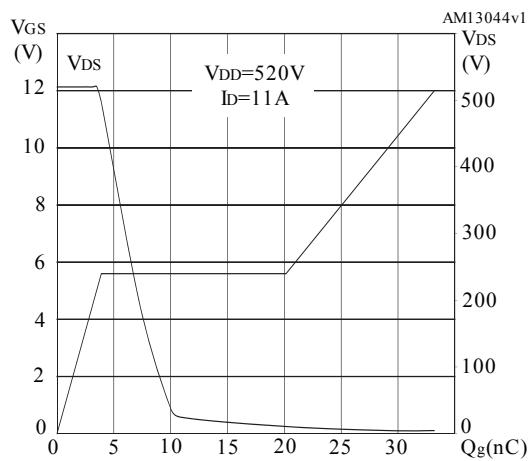
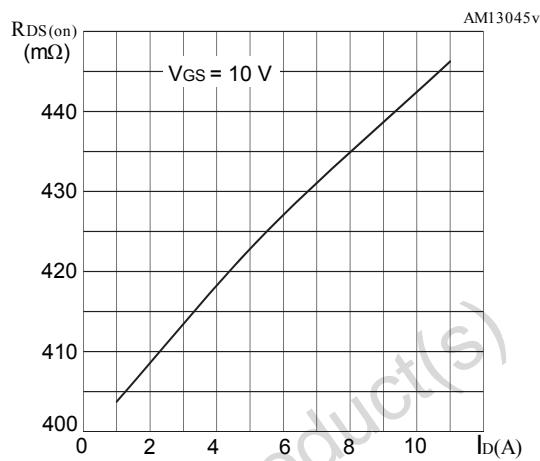
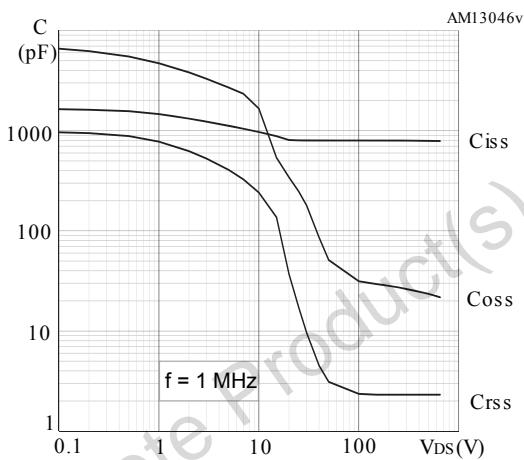
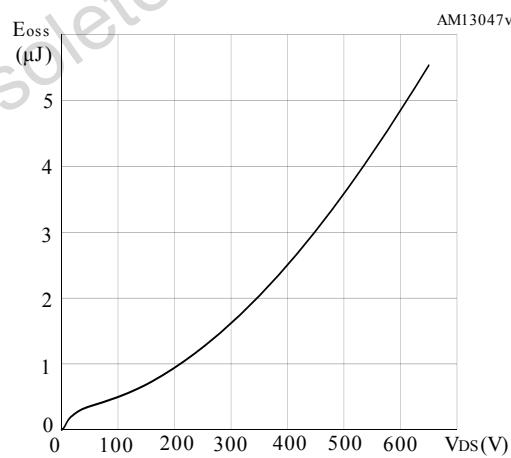
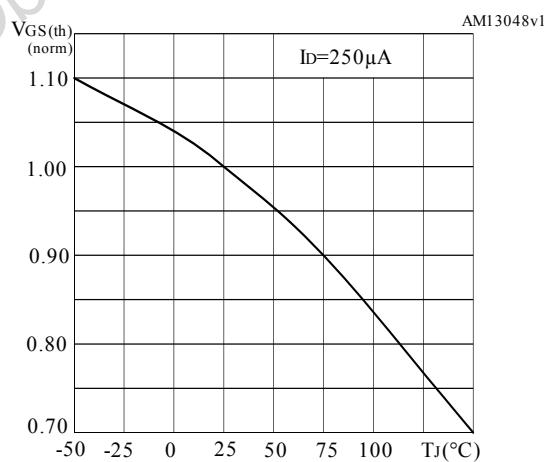
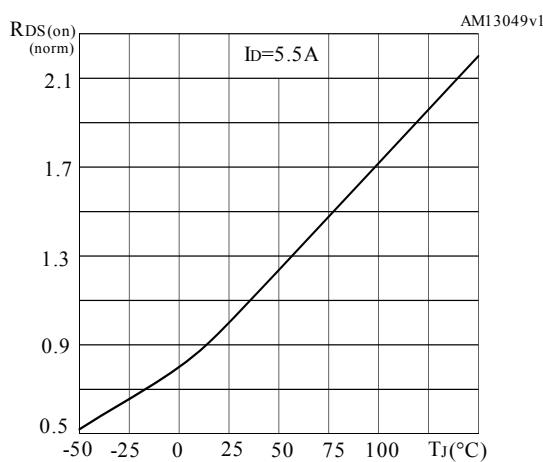
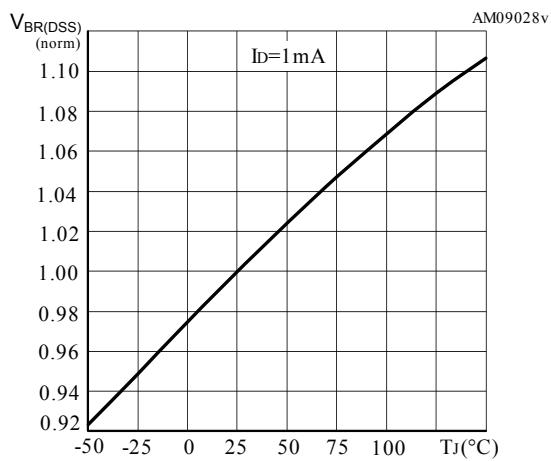
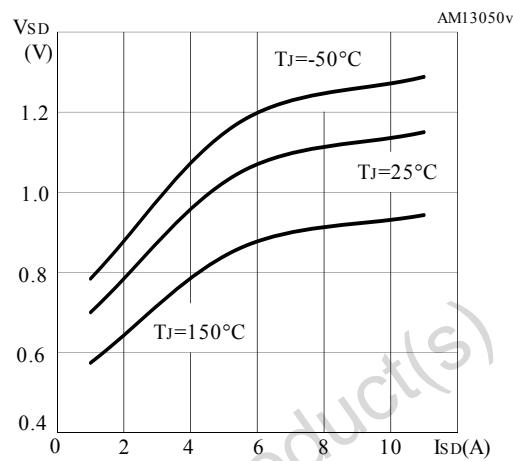
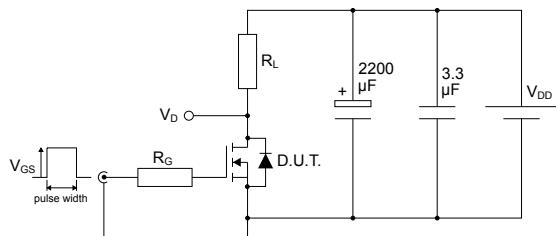
Figure 7. Typical gate charge characteristics

Figure 8. Typical drain-source on-resistance

Figure 9. Typical capacitance characteristics

Figure 10. Typical output capacitance stored energy

Figure 11. Normalized gate threshold vs temperature

Figure 12. Normalized on-resistance vs temperature


Figure 13. Normalized breakdown voltage vs temperature**Figure 14. Typical reverse diode forward characteristics**

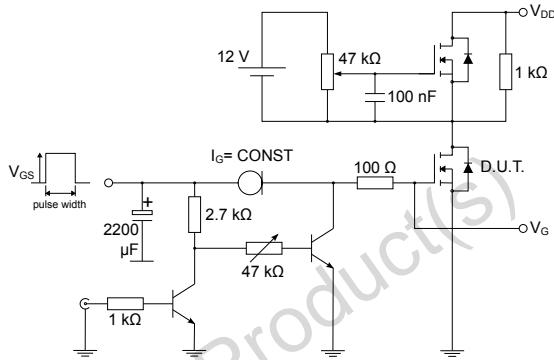
3 Test circuits

Figure 15. Test circuit for resistive load switching times



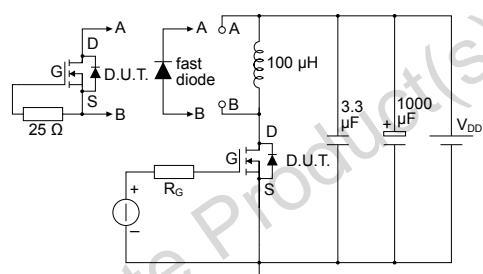
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Figure 16. Test circuit for gate charge behavior



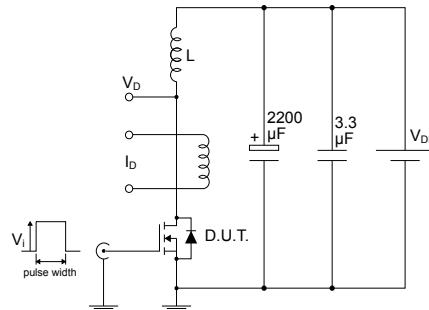
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Figure 17. Test circuit for inductive load switching and diode recovery times



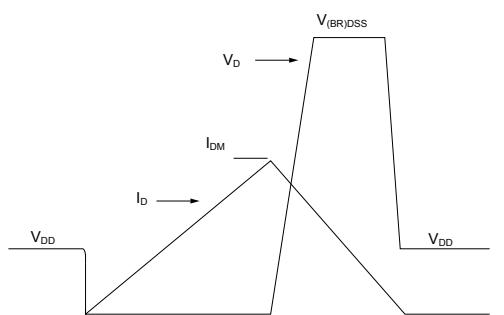
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Figure 18. Unclamped inductive load test circuit



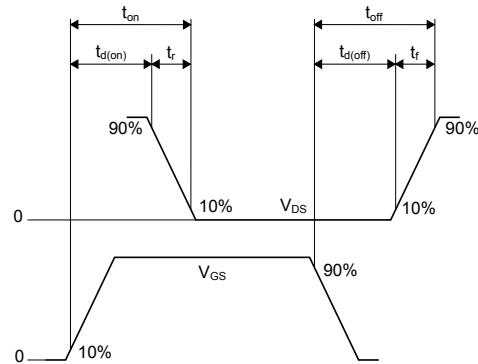
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Figure 19. Unclamped inductive waveform



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Figure 20. Switching time waveform



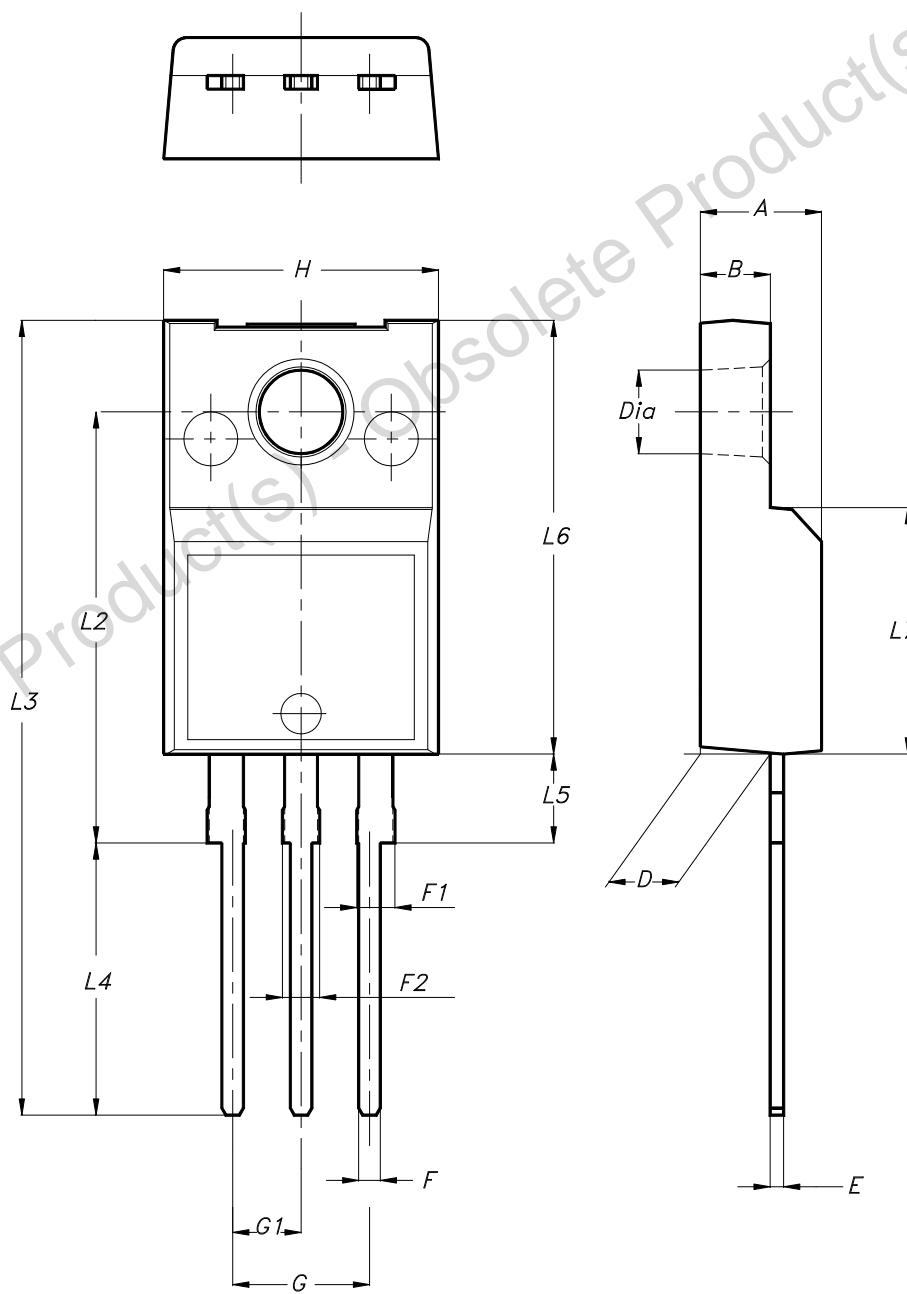
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4 Package information

In order to meet environmental requirements, ST offers these devices in different grades of **ECOPACK** packages, depending on their level of environmental compliance. ECOPACK specifications, grade definitions and product status are available at: www.st.com. ECOPACK is an ST trademark.

4.1 TO-220FP type B package information

Figure 21. TO-220FP type B package outline



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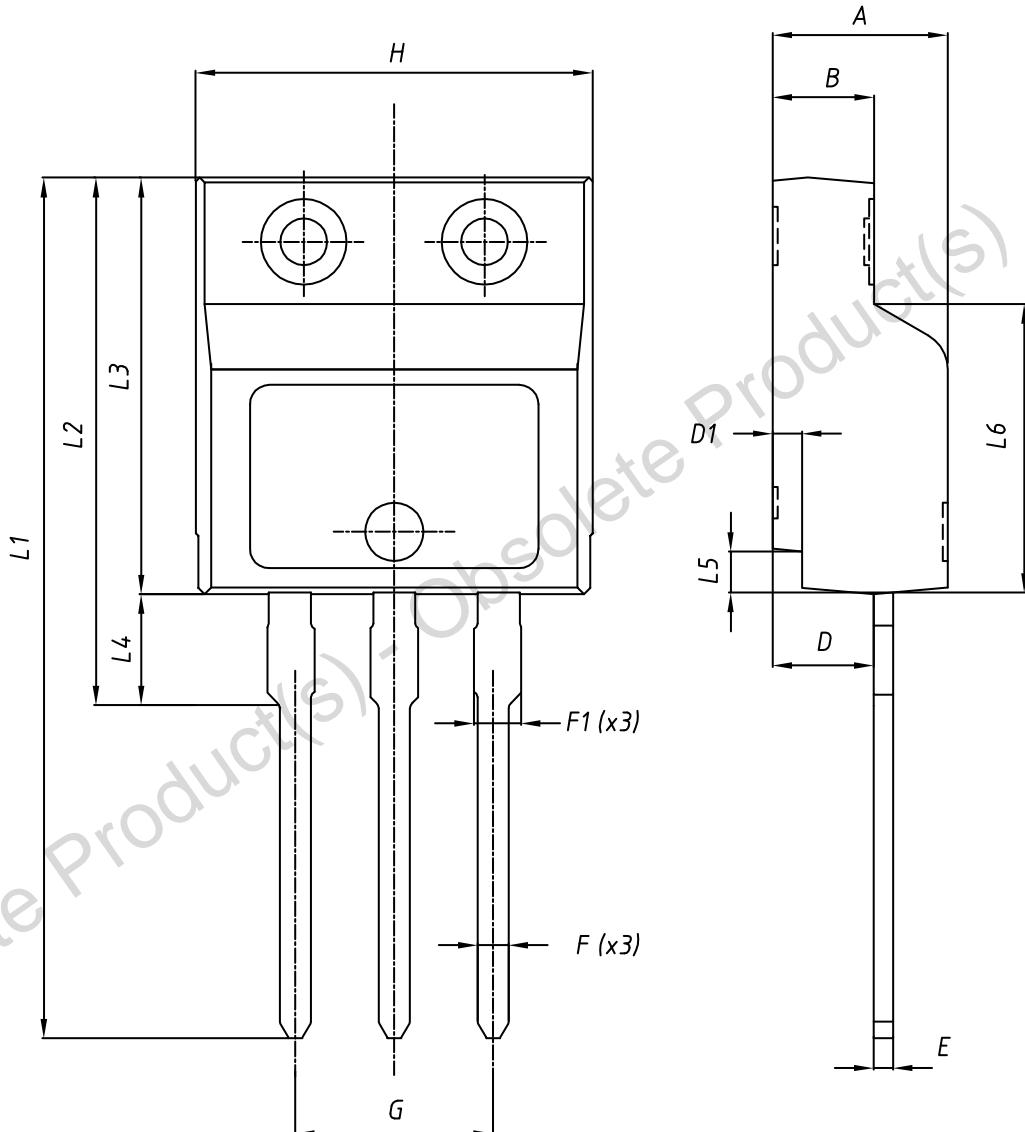
Table 7. TO-220FP type B package mechanical data

Dim.	mm		
	Min.	Typ.	Max.
A	4.40		4.60
B	2.50		2.70
D	2.50		2.75
E	0.45		0.70
F	0.75		1.00
F1	1.15		1.70
F2	1.15		1.70
G	4.95		5.20
G1	2.40		2.70
H	10.00		10.40
L2		16.00	
L3	28.60		30.60
L4	9.80		10.60
L5	2.90		3.60
L6	15.90		16.40
L7	9.00		9.30
Dia	3.00		3.20

Obsolete Product(s) - Obsolete Product(s)

4.2 I²PAKFP (TO-281) package information

Figure 22. I²PAKFP (TO-281) package outline



8291506 Rev. C

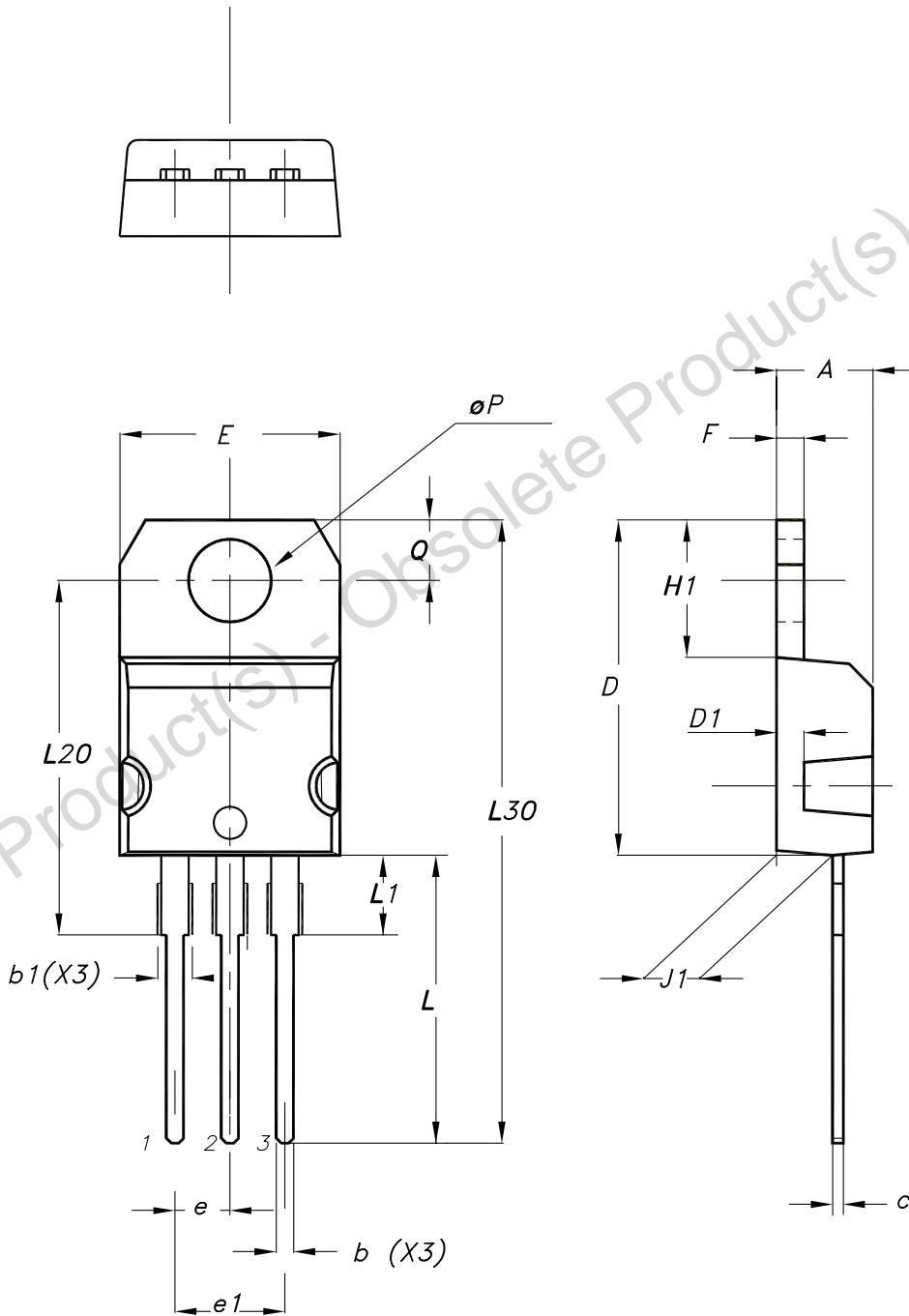
Table 8. I²PAKFP (TO-281) mechanical data

Dim.	mm		
	Min.	Typ.	Max.
A	4.40		4.60
B	2.50		2.70
D	2.50		2.75
D1	0.65		0.85
E	0.45		0.70
F	0.75		1.00
F1			1.20
G	4.95		5.20
H	10.00		10.40
L1	21.00		23.00
L2	13.20		14.10
L3	10.55		10.85
L4	2.70		3.20
L5	0.85		1.25
L6	7.50	7.60	7.70

Obsolete Product(s) - Obsolete Product(s)

4.3 TO-220 type A package information

Figure 23. TO-220 type A package outline



0015988_typeA_Rev_23

Table 9. TO-220 type A package mechanical data

Dim.	mm		
	Min.	Typ.	Max.
A	4.40		4.60
b	0.61		0.88
b1	1.14		1.55
c	0.48		0.70
D	15.25		15.75
D1		1.27	
E	10.00		10.40
e	2.40		2.70
e1	4.95		5.15
F	1.23		1.32
H1	6.20		6.60
J1	2.40		2.72
L	13.00		14.00
L1	3.50		3.93
L20		16.40	
L30		28.90	
øP	3.75		3.85
Q	2.65		2.95
Slug flatness		0.03	0.10

Obsolete Product(s) - Obsolete Product(s)

5 Ordering information

Table 10. Order codes

Order codes	Marking	Package	Packing
STF11NM65N	11NM65N	TO-220FP	Tube
STFI11NM65N		I²PAKFP	
STP11NM65N		TO-220	

Obsolete Product(s) - Obsolete Product(s)

Revision history

Table 11. Document revision history

Date	Version	Changes
08-May-2023	1	First release. Part numbers previously included in datasheet DS5257.

Obsolete Product(s) - Obsolete Product(s)

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